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	Sommario/riassunto	This book presents the select proceedings of the 7th National Conference on Advances in Metrology (AdMet 2021) organized by Maharaja Surajmal Institute of Technology, New Delhi, India. The main theme of the conference was "Sensors and Advance Materials for Measurement and Quality Improvement". The book highlights and discusses the technological developments in the areas of sensor technology, measurement, advance material for industrial application, automation and quality control. This book is aimed for all the personnel engaged in conformity assessment, quality system management, calibration and testing in all sectors of industry. The book will be a

valuable reference for metrologists, scientists, engineers, academicians and students from research institutes and industrial establishments to explore the future directions in the areas of sensors, advance materials, measurement and quality improvement. .